

650V GaN HEMT

Description

The CC65H270TOEI Series 650V, 270mΩ gallium nitride (GaN) FETs are normally-off devices.

Classicchip GaN FETs offer better efficiency through lower gate charge, faster switching speeds, and lower dynamic onresistance, delivering significant advantages over traditional silicon (Si) devices.

Classicchip is a leading-edge wide band gap supplier with world-class innovation .

Automotive

- Adapter
- Renewable energy
- Telecom and data-com
- Servo motors
- Industrial
- Automotive

General Features

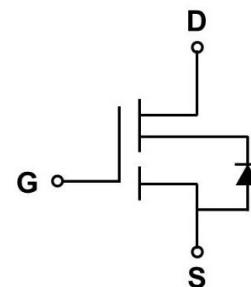
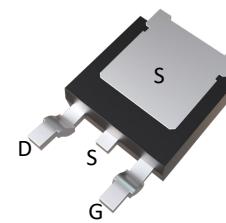
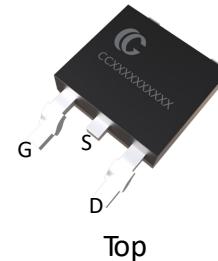
Easy to drive—compatible with standard gate drivers
 Low conduction and switching losses
 RoHS compliant and Halogen-free

Benefits

Increased efficiency through fast switching
 Increased power density
 Reduced system size and weight

Ordering Information

Part Number	Package	Package Configuration
CC65H270TOEI	TO252	Source



Circuit Symbol

Features

BV_{DSS}	$R_{DS(on)}$	I_{DS}	Q_G
650V	270mΩ	7.9A	7.9nC

Absolute Maximum Ratings

$T_C=25^\circ\text{C}$ unless otherwise stated

Symbol	Parameter	Limit value	Unit
V_{DSS}	Drain to source voltage ($T_J = -55^\circ\text{C}$ to 150°C)	650	
$V_{(\text{TR})DSS}$	Drain to source voltage-transient ^a	800	V
V_{GSS}	Gate to source voltage	-20~+20	
I_D	Continuous drain current @ $T_C=25^\circ\text{C}$ ^b	7.9	
	Continuous drain current @ $T_C=125^\circ\text{C}$ ^b	3.5	A
I_{DM}	Pulse drain current (pulse width: 100μs)	14	A
P_D	Maximum power dissipation @ $T_C=25^\circ\text{C}$	32	W
T_C	Operating temperature	Case	$-55\text{~}150$ $^\circ\text{C}$
T_J		Junction	$-55\text{~}150$ $^\circ\text{C}$
T_S	Storage temperature	-55~150	$^\circ\text{C}$

a. In off-state, spike duty cycle D<0.01, spike duration <1μs

b. For increased stability at high current operation

Thermal Resistance

Symbol	Parameter	Limit value	Unit
$R_{\theta JC}$	Junction-to-case	3.9	°C /W

Electrical Parameters

T_J=25°C unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Forward Device Characteristics						
V _{(BL)DSS}	Drain-source voltage	650	-	-	V	V _{GS} = 0V
V _{GS(th)}	Gate threshold voltage	-	4	-	V	
ΔV _{GS(th)/T_J}	Gate threshold voltage temperature coefficient	-	-7	-	mV/°C	V _{DS} =1V, I _{DS} =1mA
R _{DS(on)}	Drain-source on-resistance	-	270	320	mΩ	V _{GS} =10V, I _D =1A, T _J =25°C
		-	570	-		V _{GS} =10V, I _D =1A, T _J =150°C
I _{DSS}	Drain-to-source leakage current	-	-	10	μA	V _{DS} =650V, V _{GS} = 0V, T _J =25°C
		-	-	100		V _{DS} =650V, V _{GS} = 0V, T _J =150°C
I _{GSS}	Gate-to-source forward leakage current	-	-	±100	nA	V _{GS} =±20V
C _{ISS}	Input capacitance	-	293	-		
C _{OSS}	Output capacitance	-	17	-	pF	V _{GS} =0V, V _{DS} =400V, f=1MHz
C _{RSS}	Reverse capacitance	-	3.74	-		
Q _G	Total gate charge	-	7.9	-		
Q _{GS}	Gate-source charge	-	2.31	-	nC	V _{DS} =400V, V _{GS} =0V to 10V, I _D =1A
Q _{GD}	Gate-drain charge	-	1.65	-		
Q _{OSS}	Output charge	-	22.2	-	nC	V _{GS} =0V, V _{DS} =0V to 400V, f=1MHz
t _{D(on)}	Turn-on delay	-	3.2	-		
t _R	Rise time	-	5.5	-	ns	V _{DS} =400V, V _{GS} =0V to 10V, I _D =2.1A, R _{G-on(ext)} =6.8Ω, R _{G-off(ext)} =2.2Ω, L=250μH
t _{D(off)}	Turn-off delay	-	7.4	-		
t _F	Fall time	-	27	-		

Electrical Parameters

T_J=25°C unless otherwise stated

Symbol	Parameter	Min	Typ	Max	Unit	Test Conditions
Reverse Device Characteristics						
V _{SD}	Source-Drain reverse voltage	-	2.3	-	V	V _{GS} =0V, I _{SD} =5A
t _{RR}	Reverse recovery time	-	14	-	ns	
Q _{RR}	Reverse recovery charge	-	6.5	-	nC	I _F =10A, V _{DD} =400V, dI _F /dt=165A/μs

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

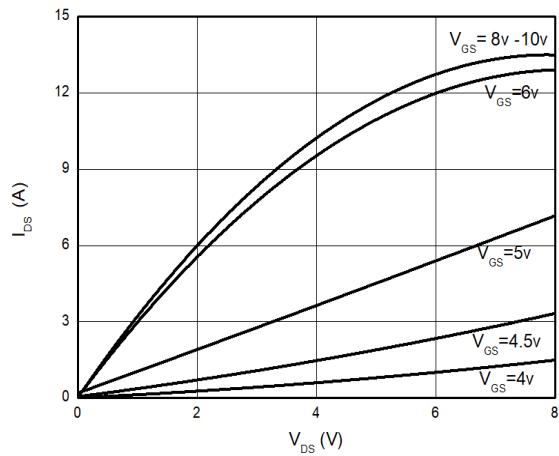


Figure 1. Typical Output Characteristics $T_J=25^\circ\text{C}$

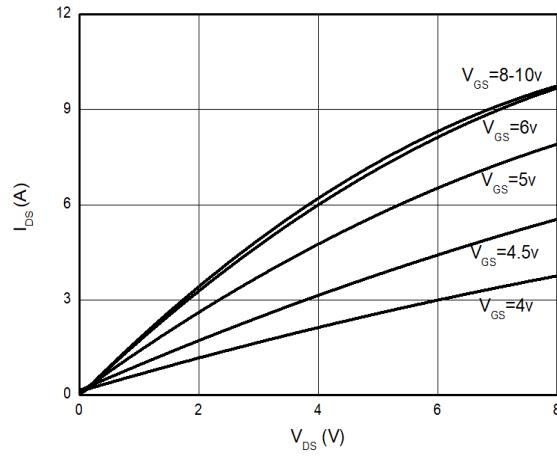


Figure 2. Typical Output Characteristics $T_J=125^\circ\text{C}$

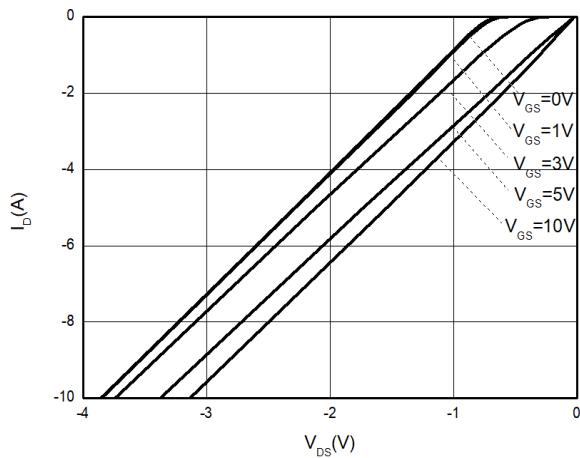


Figure 3. Channel Reverse Characteristics $T_J=25^\circ\text{C}$

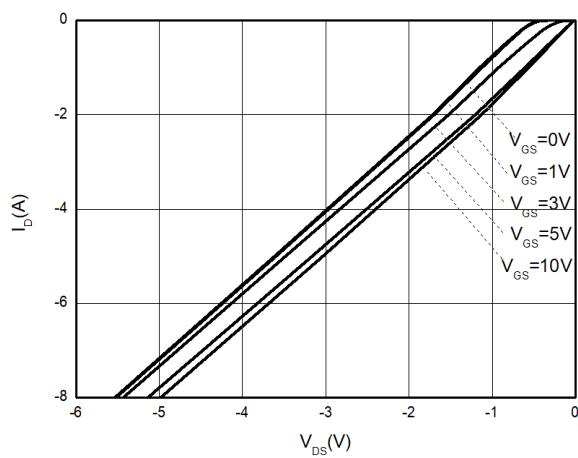


Figure 4. Channel Reverse Characteristics $T_J=125^\circ\text{C}$

Typical Characteristics

T_J=25°C unless otherwise stated

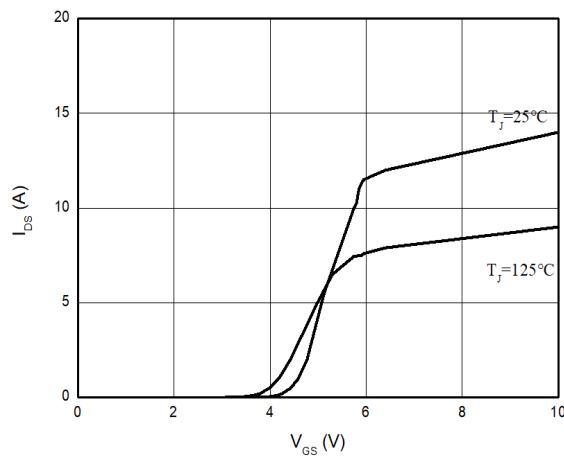


Figure 5. Typical Transfer Characteristics ($V_{DS}=5\text{V}$)

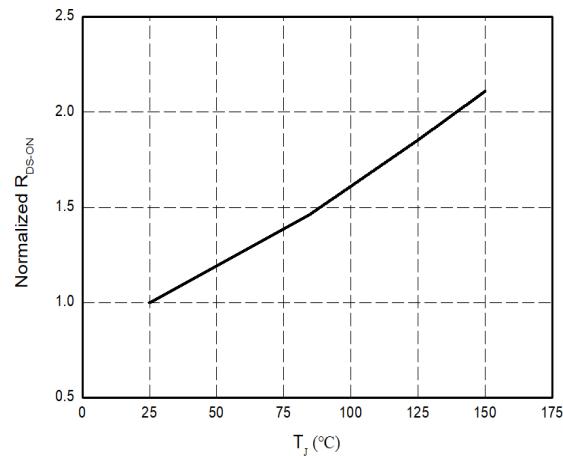


Figure 6. Normalized On-resistance

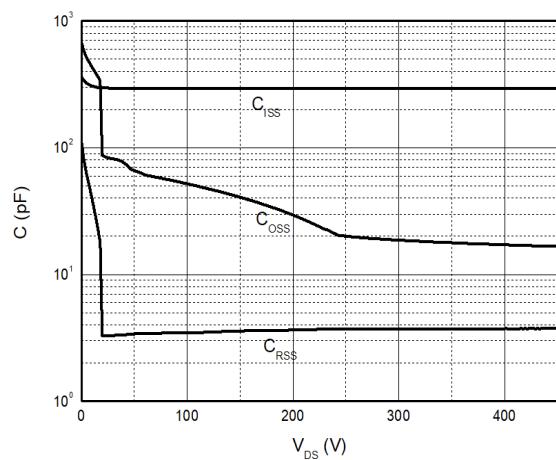


Figure 7. Typical Capacitance ($f=1\text{MHz}$)

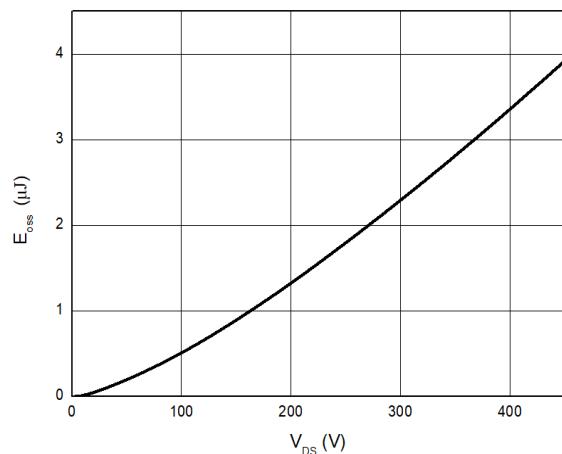


Figure 8. Typical C_{OSS} Stored Energy

Typical Characteristics

T_J=25°C unless otherwise stated

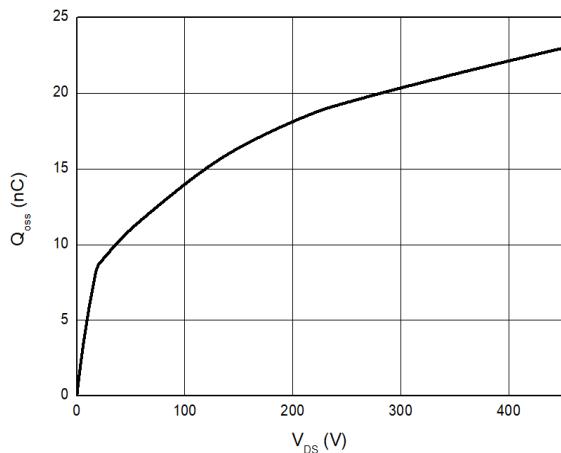


Figure 9. Typical Q_{oss}

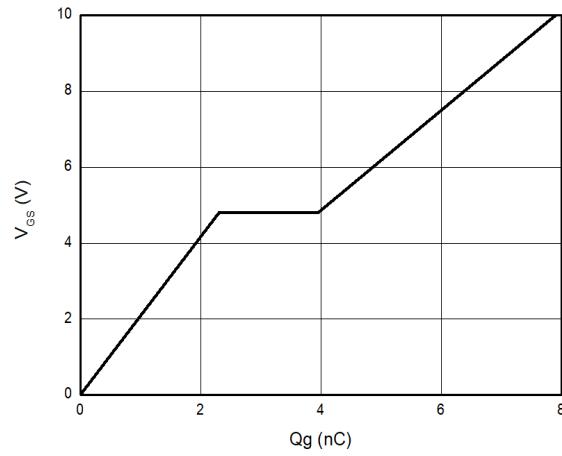


Figure 10. Typical Gate Charge (V_{DS}=400V, I_D=1A)

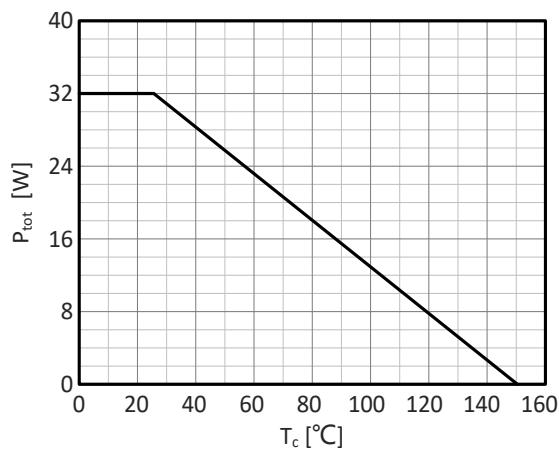


Figure 11. Power Dissipation

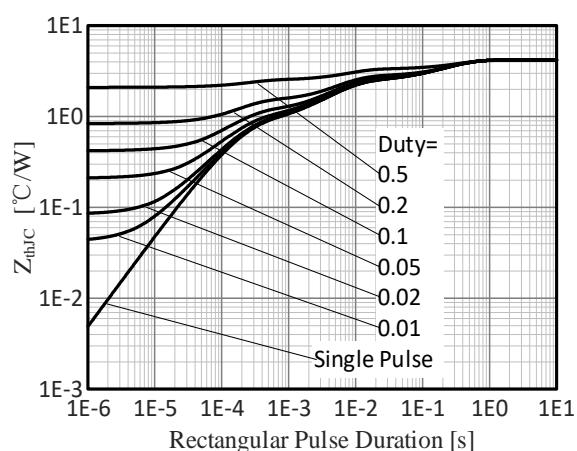


Figure 12. Transient Thermal Resistance

Typical Characteristics

$T_J=25^\circ\text{C}$ unless otherwise stated

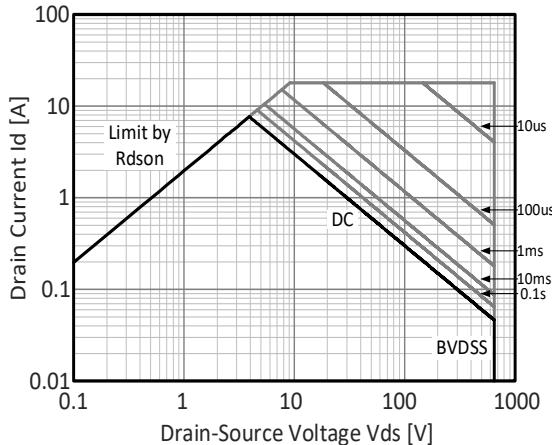


Figure 13. Safe Operating Area $T_c=25^\circ\text{C}$

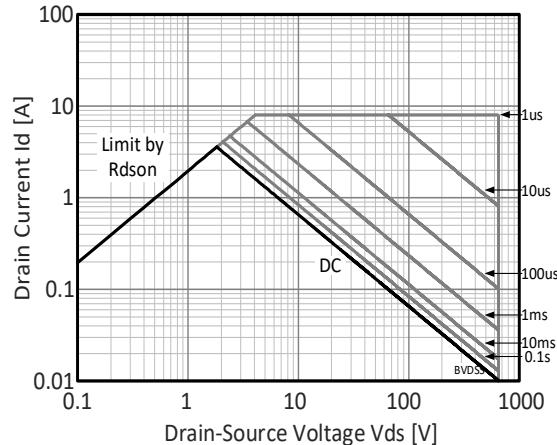


Figure 14. Safe Operating Area $T_c=125^\circ\text{C}$

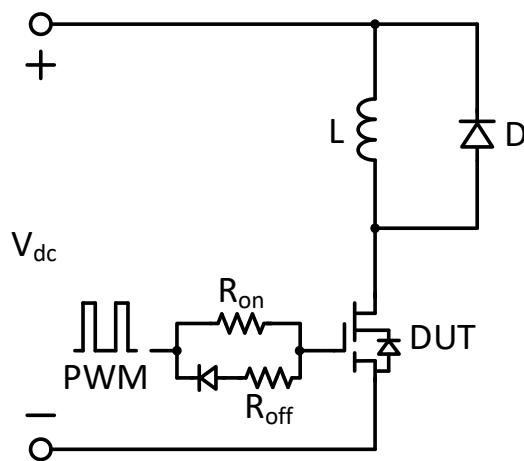


Figure 15. Switching times with inductive load

$$V_{DS}=400\text{V}, V_{GS}=0\text{V to } 10\text{V}, I_D=2.1\text{A}, \\ R_{G-on(ext)}=6.8\Omega, R_{G-off(ext)}=2.2\Omega, L=250\mu\text{H}$$

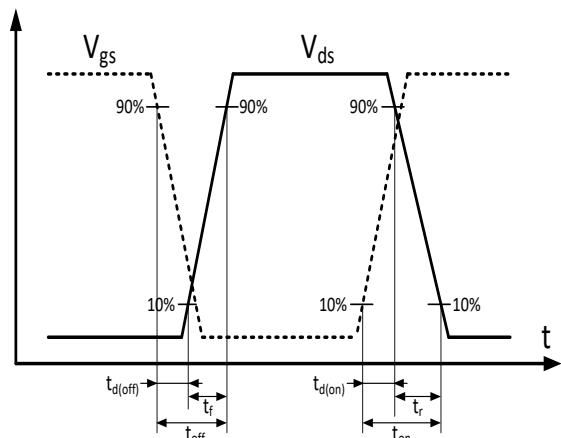
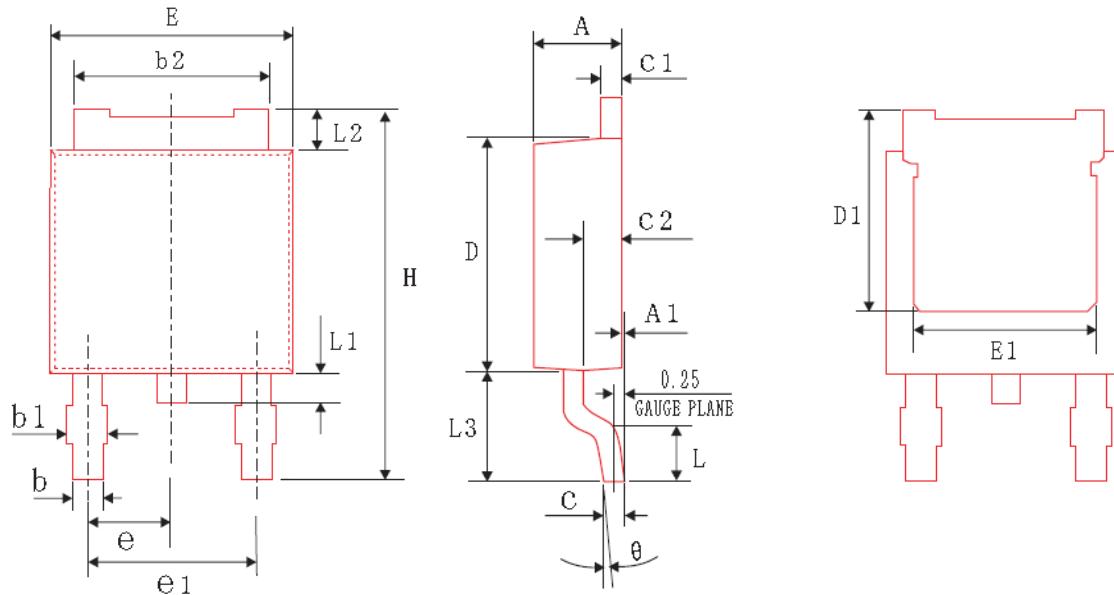
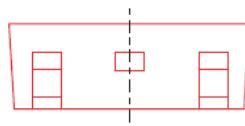


Figure 16. Switching times with waveform

PACKAGE DIMENSIONS

TO252-2L


TOP VIEW
SIDE VIEW
BOTTOM VIEW

SIDE VIEW

 COMMON DIMENSIONS
 (UNITS OF MEASURE-mm)

SYMBOL	MIN	NOM	MAX
A	2.20	2.30	2.40
A1	0.00	0.05	0.10
b	0.762	0.812	0.862
b1	—	—	1.10
b2	5.23	5.33	5.43
c	0.458	0.508	0.558
C1	0.458	0.508	0.558
C2	0.80	1.00	1.20
D	6.00	6.10	6.20
D1	5.25	5.45	5.65
H	10.00	10.10	10.20
E	6.50	6.60	6.70
E1	4.75	4.85	4.95
e1	4.37	4.57	4.77
L	—	—	1.45
L1	0.60	0.75	0.90
L2	0.90	1.10	1.30
L3	2.80	3.00	3.20
θ	0°	4°	8°
e	2.285 BSC		